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Certified Reference Material

Certificate of Analysis

ISO 17034:2016





Product ID: IARM-Cu172-19

Product Description: Beryllium Copper, CDA 172 / C17200

Description and Intended Use: This **Certified Reference Material** is covered under the scope of accreditation to **ISO 17034** by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in **ISO 17025** accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Certified values listed in wt.% with associated uncertainties											
Ag	0.0011	± 0.0003	Αl	0.032	± 0.001	Be	1.89	± 0.02	Co	0.0017	± 0.0004
Cr	0.0017	± 0.0001	Fe	0.071	± 0.002	Mg	0.112	± 0.003	Mn	0.0019	± 0.0003
Ni	0.237	± 0.008	Р	0.0036	± 0.0008	S	0.0010	± 0.0004	Sb	0.0007	± 0.0002
Si	0.045	± 0.002	Sn	0.0007	± 0.0002						

Indicative Values listed in ppm

As (40) Bi (4) Cd (40) Cu (97.6%) Pb (40) Se (10) Zn (30)

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where H=U_{hom}, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1.
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards Manchester, NH
- Dirats Laboratories Westfield, MA
- NSL Analytical Services Cleveland, OH
- Laboratory Testing, Inc. Hatfield, PA
- TEC Eurolab Campogalliano, Italy
 Applied Technical Services Marietta, GA
- Connecticut Metallurgical, Inc. East Hartford, CT IMR Test Labs Lansing, NY
- SGS MSi Melrose Park II
- SGS MSi Melrose Park, IL Scrooby's Laboratory Service - Rynfield, South Africa
- Universal Scientific Laboratory Revesby, Australia
- Sheffield Assay Office Sheffield, UK
- EAG Laboratories Liverpool, NY
- TCR Engineering Services Maharashtra, India
- Institute of Non-Ferrous Metals Gliwice, Poland
- AnchorCert Analytical Birmingham, UK

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Kimberly Halkiotis, Global Product Manager

November 5, 2021 Certification Date



ISO 17034 Accredited: Reference Materials Producer, Certificate # 2848.02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	Al	As	Be	Bi	Cd	Co	Cr	Cu	Fe	Mg	Mn	Ni
1	0.0004	0.0260	0.0005	1.8180	0.0001	0.0007	0.0004	0.0015	97.400	0.0608	0.1050	0.0018	0.2190
2	0.0007	0.0270	0.0006	1.8220	0.0001	0.0000	0.0006	0.0015	97.400	0.0620	0.1060	0.0006	0.2200
3	0.0008	0.0290	0.0010	1.8580	0.0001	0.0001	0.0015	0.0015	97.500	0.0666	0.1070	0.0010	0.2200
4	0.0008	0.0300	0.0011	1.8600	0.0002	0.0002	0.0016	0.0015	97.530	0.0679	0.1080	0.0010	0.2230
5	0.0010	0.0306	0.0012	1.8800	0.0005	0.0020	0.0017	0.0015	97.580	0.0680	0.1080	0.0017	0.2250
6	0.0010	0.0310	0.0012	1.8830	0.0010	0.0060	0.0017	0.0017	97.650	0.0690	0.1082	0.0020	0.2265
7	0.0010	0.0310	0.0014	1.8860	0.0010	0.0070	0.0017	0.0017	97.690	0.0690	0.1090	0.0020	0.2270
8	0.0011	0.0312	0.0016	1.8930	<0.0001	0.0100	0.0017	0.0017	97.810	0.0700	0.1106	0.0021	0.2308
9	0.0012	0.0316	0.0016	1.9000	<0.0001	0.0110	0.0017	0.0017		0.0700	0.1120	0.0022	0.2320
10	0.0012	0.0318	0.0027	1.9010	<0.001	<.00005	0.0020	0.0018		0.0704	0.1140	0.0022	0.2330
11	0.0013	0.0320	0.0070	1.9043	<0.001	<0.0001	0.0020	0.0018		0.0710	0.1150	0.0022	0.2340
12	0.0016	0.0320	0.0070	1.9240	<0.001	< 0.0005	0.0020	0.0019		0.0720	0.1160	0.0022	0.2360
13	0.0018	0.0322	0.0070	1.9250	<0.001	< 0.0005	0.0020	0.0020		0.0723	0.1163	0.0022	0.2380
14	0.0020	0.0322	0.0080	1.9550	< 0.002	< 0.001	0.0020	0.0020		0.0730	0.1170	0.0022	0.2398
15	< 0.0001	0.0325	0.0080		<0.002	<0.001	0.0036	0.0020		0.0733	0.1175	0.0025	0.2500
16	< 0.0005	0.0330	0.0101		<0.002	<0.005	< 0.002	0.0020		0.0735	0.1180	<0.001	0.2521
17	< 0.002	0.0331	<0.001		<0.005		< 0.002	<0.0005		0.0737	0.1210	<0.002	0.2610
18	<0.005	0.0348	<0.005				<0.005	<0.002		0.0740		<0.002	0.2710
19		0.0350	< 0.005					< 0.002		0.0752		<0.002	0.2740
20		0.0354						< 0.002		0.0786		<0.005	
21		0.0357						<0.005		0.0791			
Mean	0.0011	0.0318	0.0038	1.8864	0.0004	0.0041	0.0017	0.0017	97.570	0.0709	0.1123	0.0019	0.2375
STDV	0.0004	0.0025	0.0034	0.0380	0.0004	0.0044	0.0007	0.0002	0.1428	0.0045	0.0049	0.0006	0.0167
Certified	0.0011	0.032	(0.004)	1.89	(0.0004)	(0.004)	0.0017	0.0017	(97.6)	0.071	0.112	0.0019	0.237
U _{CRM}	0.0003	0.001		0.02	<u> </u>		0.0004	0.0001		0.002	0.003	0.0003	0.008
Methods	I,IM,O,X,A	I,O,IM,X	I,IM,O,X	O,I	I,IM,O,X	I,O,IM,X,A	I,IM,O,X	I,IM,O,X	O,W,I,X	I,O,IM,X,A	I,O,IM,A	I,IM,O,X,A	I,O,IM,X,A

	P	Pb	S	Sb	Se	Si	Sn	Zn
1	0.0020	0.0031	0.0004	0.0003	0.0002	0.0370	0.0002	0.0006
2	0.0020	0.0009	0.0004	0.0004	0.0003	0.0394	0.0003	0.0010
3	0.0021	0.0010	0.0007	0.0006	0.0013	0.0404	0.0003	0.0019
4	0.0023	0.0010	0.0013	0.0007	0.0015	0.0410	0.0003	0.0025
5	0.0027	0.0010	0.0014	0.0007	0.0017	0.0410	0.0004	0.0026
6	0.0028	0.0010	0.0014	0.0007	0.0025	0.0410	0.0005	0.0027
7	0.0028	0.0011	0.0014	0.0008	<.00005	0.0425	0.0005	0.0030
8	0.0029	0.0018	<0.0001	0.0009	<0.0001	0.0434	0.0007	0.0031
9	0.0030	0.0019	<0.0005	0.0010	<0.0001	0.0440	0.0010	0.0032
10	0.0032	0.0020	<0.001	0.0010	<0.0005	0.0440	0.0010	0.0033
11	0.0033	0.0021	<0.001	0.0010	<0.0005	0.0446	0.0010	0.0035
12	0.0035	0.0047	<0.001	<0.0005	<0.001	0.0446	0.0011	0.0036
13	0.0042	0.0060	<0.002	< 0.001	<0.002	0.0460	0.0013	0.0038
14	0.0050	0.0060	<0.002	< 0.001	<0.005	0.0460	<0.0006	0.0040
15	0.0060	0.0070	<0.002	< 0.002	< 0.005	0.0477	< 0.001	0.0049
16	0.0060	0.0070	< 0.003	< 0.002		0.0480	< 0.001	0.0050
17	0.0070	0.0091		< 0.002		0.0484	< 0.001	0.0070
18	<0.002	0.0100		< 0.005		0.0485	<0.002	<0.002
19	<0.005	0.0120				0.0500	<0.002	<0.002
20	< 0.005	<0.001				0.0570	<0.002	<0.002
21							<0.005	<0.005
Mean	0.0036	0.0041	0.0010	0.0007	0.0013	0.0447	0.0007	0.0033
STDV	0.0015	0.0035	0.0005	0.0002	0.0009	0.0045	0.0004	0.0015
Certified	0.0036	(0.004)	0.0010	0.0007	(0.001)	0.045	0.0007	(0.003)
UCRM	0.0008		0.0004	0.0002		0.002	0.0002	
Methods	I,O,IM,X,W,A	I,IM,O,X,A	C,O,I,X	IM,O,I,X,A	I,O,IM,X	I,O,IM,X,W	I,IM,O,X	I,IM,O,X,A

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES